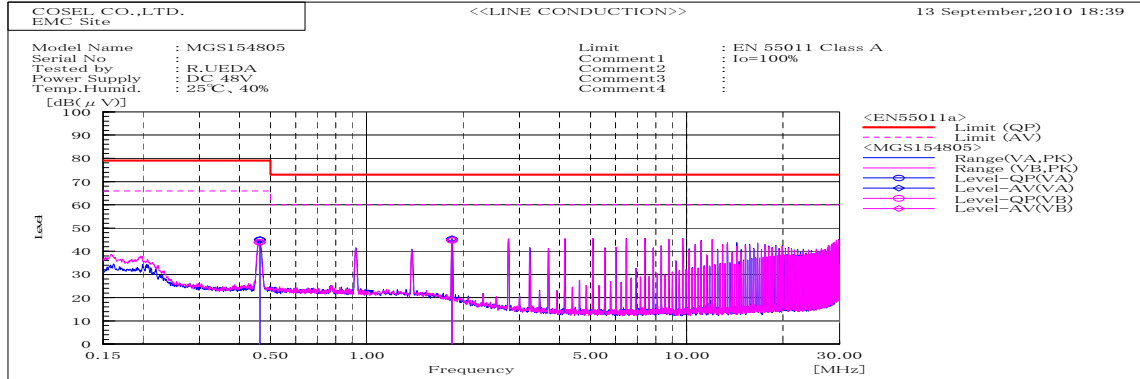
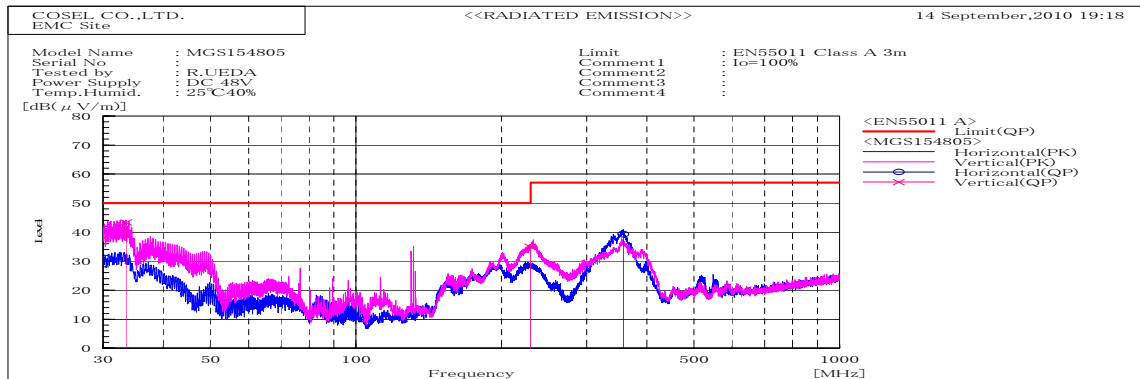


DATA SHEET		Date	21-Sep-10
Model	MGS154805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.46299		VB	33.9	33.9	10	43.9	43.9	79	66	35.1	22.1	Pass	
0.46334		VA	34.8	35	10.1	44.9	45.1	79	66	34.1	20.9	Pass	
1.84704		VA	35	35.2	10.1	45.1	45.3	73	60	27.9	14.7	Pass	
1.84888		VB	34.5	34.9	10.1	44.6	45	73	60	28.4	15	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
33.477	V	Stable	58.5	-15.2		43.3		50	6.7	Pass	102	359	
229.44	V	Stable	54.6	-19.7		34.9		50	15.1	Pass	104	299	
357.103	H	Stable	55.3	-16		39.3		57	17.7	Pass	101	165	

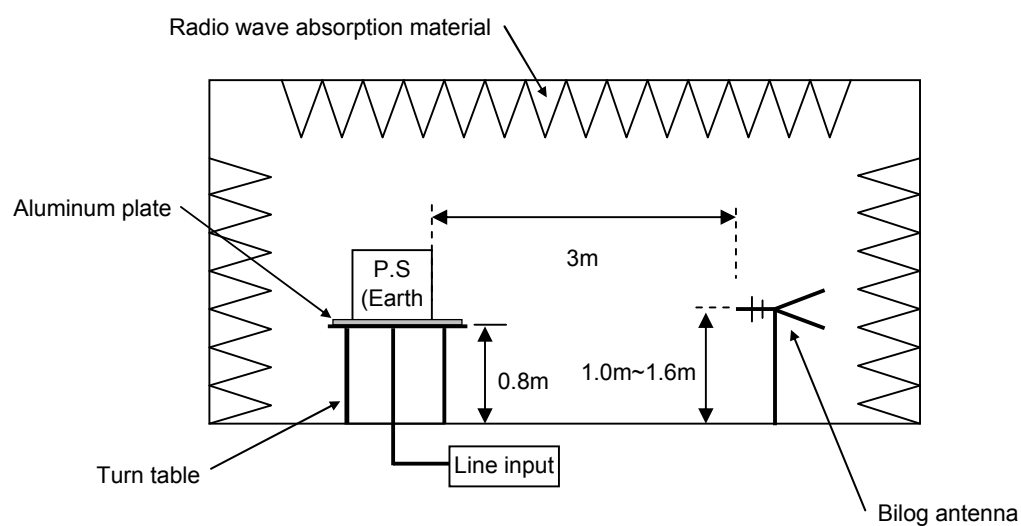
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission



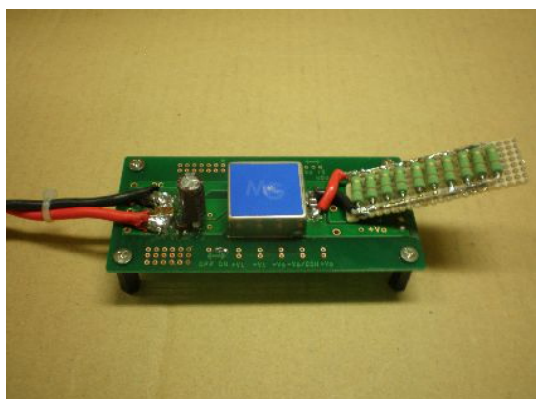


Conditions

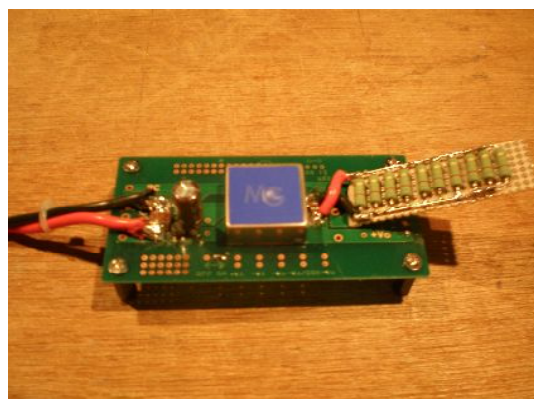
Test : EMI
Model Name : MGS1548□□/MGW1548□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

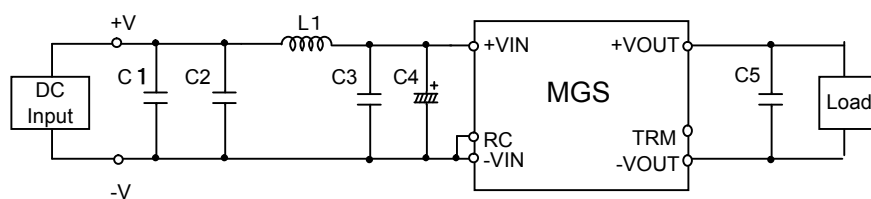


Fig.1 Testing circuitry 1

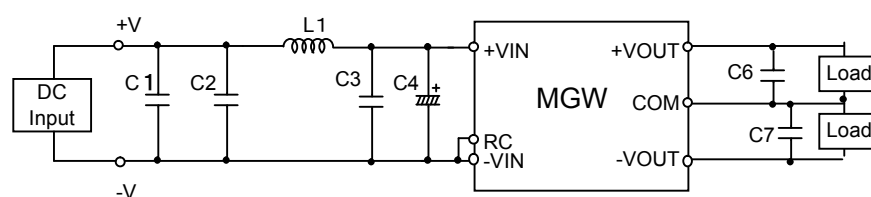


Fig.2 Testing circuitry 2

L1	: 10 μ H	CI4C-100	(KORIN ELECTRONICS)
C1,C2,C3	: 100V	2.2 μ F	C4532JB2A225MT (TDK)
C4	: 80V	47 μ F	LXV80VB47M (NIPPON CHEMI-CON)
C5,C6,C7	: 25V	22 μ F	CM32X5R226K25A (KYOCERA)